

Notice of References Cited	Application/Control No. 10/537,830	Applicant(s)/Patent Under Reexamination HIRAI, HIDEAKI	
	Examiner TAN X. DINH	Art Unit 2627	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,050,383 b2	05-2006	Nakajima et al.	369/275.3
*	B	US-6,906,994 b2	06-2005	Lee et al.	369/275.4
*	C	US-5,926,446 a	07-1999	Shimizu, Akihiko	369/275.4
*	D	US-6,930,977 b1	08-2005	Kondo et al.	369/275.4
*	E	US-5,410,534 a	04-1995	Nagata et al.	369/275.4
*	F	US-6,678,236 b1	01-2004	Ueki, Yasuhiro	369/275.3
*	G	US-6,965,556 b1	11-2005	Kikukawa et al.	369/275.4
*	H	US-6,762,989 b2	07-2004	Hirokane et al.	369/275.4
*	I	US-5,946,287 a	08-1999	Nakayama et al.	369/275.4
*	J	US-6,175,548 b1	01-2001	Kashiwagi, Toshiyuki	369/275.1
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.